P1450.4 meeting minutes - 05/26/04

Attendees: Dan Fan, Jose Santiago, Jim O'Reilly, Ernie Wahl, Dave Dowding, Jim Mosley
Not present: Eric Nguyen, Yuhai Ma, Don Organ, Tom Micek, Tony Taylor, Doug Sprague

Summary:

Didn't have a quorum (50%+) until about ½ hour into the meeting. As a result, no formal agenda was set, but instead, we just reviewed the recent activities for the benefit of those who hadn't been able to join the meetings recently.

Jose: Can meeting minutes be posted on the IEEE STIL web site? People who monitor the IEEE STIL web sites are not kept abreast of our activities.

Jim: There's currently a link from the IEEE web site to the web site that Don Organ maintains. Can it be made more obvious? Or more widely advertised? I'll talk to Dave and Tony about what to do about this.

Jim: Reviewed briefly the two subgroups set up during the May 5 (?) meeting – the conceptual model subgroup (Dave Dowding, Ernie Wahl, ???), and the syntax subgroup (Tony Taylor, Don Organ, Jim O'Reilly).

Jim: Review for Jose (and others) about recent activity regarding conceptual model.

Jose expressed interest in being part of the syntax subgroup. Asked if there was any activity in this group yet.

Jim: As yet, this subgroup hasn't established a working routine.

Jose: Mark Roos of Roos Instruments expressed interest in learning more about the STIL .4 activities. Roos Instruments (an STC member) has already implemented a complete object-oriented language for its mixed-signal testers, and is interested in seeing whether STIL can include some of the concepts and constructs they've implemented. Roos was leaning towards using OTPL, but also wants to explore whether STIL may be a better fit.

The .4 working group would welcome participation by Roos Instruments.

Comment: Note that Roos' products are primarily mixed-signal and RF test systems. STIL, in its current incarnations, is focussed on digital test, and as such, has minimal support for mixed-signal/RF test. The requirements of non-digital test are not likely to have a major effect on the test flow portion of STIL, except perhaps in the proposed **result** field of the test harness, which may need to be extended from a simple scalar or one-dimensional array of int/float/… to perhaps a multi-dimensional array. However, other portions of STIL (such as STIL.5 – test methods – or existing parts of STIL, such as STIL.0 and STIL.2) will be more heavily impacted by the requirements of non-digital test – and that's outside the scope of this WG's activities.

At this point, a longish discussion about harness/defaults/etc (initiated by Ernie) ensued. The harness will probably not be directly manifested in the syntax, but may appear implicitly in our decision about how to organize the defaults into different sections. Much back and forth discussion on this topic.